

Notice of References Cited	Application/Control No. 10/051,829	Applicant(s)/Patent Under Reexamination MIYAKE, TOMOYUKI	
	Examiner Christopher R. Magee	Art Unit 2653	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,512,731	01-2003	Seo et al.	720/656
	B	US-5,572,498	11-1996	Choi, Hyungho	720/627
	C	US-5,812,511	09-1998	Kawamura et al.	720/616
	D	US-5,923,630	07-1999	Yoshida et al.	720/720
	E	US-5,995,345	11-1999	Overbo, David M.	360/133
	F	US-6,108,299	08-2000	Kano et al.	720/734
	G	US-6,122,142	09-2000	Kabasawa, Hidetoshi	360/99.06
	H	US-6,262,960	07-2001	Watanabe, Toshio	720/615
	I	US-6,310,855	10-2001	Choi, Han-kook	720/720
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05047155 A	02-1993	Japan	FUJISAWA, HIROTOSHI	G11B 23/30
	O	JP 10199203 A	07-1998	Japan	WATANABE et al.	G11B 23/30
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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